



Accelerating Advance Display Fab Yield Ramps with Novel Display Yield Equipment (DYE)

Ecosystem

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Modern high resolution OLED and LCD display manufacturing requires greater emphasis on defect reduction and process control. Applied Materials' world first inline Electron Beam Review (EBR) system integrates Semiconductor SEM with AKT's large-scale vacuum platform. Auto process inspection (API) and critical dimensions (CDs) measurement enable customers' most challenging process control spec. Features a precision stage, auto defects review (ADR) module registers the defects based on AOI coordinates and determines root cause of killer defects aided with EDX. Bringing Semiconductor yield methods of inline SEM enables high yielding reliable flexible OLED displays and accelerates world largest substrate LCD yield ramp.

Biography

Education:

- Yong Gao holds a Ph.D. in Material Science and Engineering from The University of Arizona.

Experience:

- Dr. Yong Gao is currently working as Senior Business Development Manager for Applied Materials Display and Flexible Technology Group, where he is responsible for assisting display customers improve the yield with E-beam review and testing products. Prior to Applied Materials, Yong Gao served more than 10 years with KLA-Tencor, a supplier of process control and yield management solutions for the semiconductor and related industries, where he held positions in product development and marketing of Inspection and Metrology systems.